

## A compact, low-field, broadband matching section for externallypowered X-band dielectric-loaded accelerating structures

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## Introduction

- Slow wave accelerators: dielectric-loaded accelerating (DLA) structures


Ez of the TM01 mode $\left(v_{\mathrm{p}}=c\right)$

| dielectric |
| :---: |
| Vacuum |
| dielectric |

## Advantages of DLA:

* Simple geometry for easy fabrication;
* No field enhancements on irises;
* Potential high gradient;
* Easy to damp HOMs;

Disadvantages of DLA:

* Low power efficiency due to high group velocity $>10 \%$ of $c$


## Dielectric RF property



Courtesy of photo from Dr. Chunguang Jing, Euclid Techlabs.

- $\mathrm{A} \mathrm{TE}_{01 \delta}$ silver-plated resonator with a high quality factor, which is designed for testing ceramics at an X -band frequency, is used to measure the dielectric constant $\varepsilon_{r}$ and loss tangent $\tan \delta$ of sample coupons.
- Four dielectric coupons made from the same dielectric rods as for the fabrication of the DLA structure are measured.
- A dielectric constant $\varepsilon_{r}=16.66$ and an ultralow loss tangent $\tan \delta=3.43 \times$ $10^{-5}$ (having error bars $0.6 \%$ of the nominal value) are obtained for the RF design of the DLA structure and matching sections which follows.


## An X-band DLA structure



## RF parameters for a DLA



|  |  |
| :---: | :---: |
| $E_{\mathrm{S}_{-} \text {_acuum }} / E_{\mathrm{a}}$ | 1.07 |
| $E_{\mathrm{s}_{\text {_dielectric }}} / E_{\mathrm{a}}$ | 1.00 |
| $E_{\mathrm{s}_{\text {_metal }}} / E_{\mathrm{a}}$ | 0.206 |
| $H_{\mathrm{s}_{-} \text {vacuum }} / E_{\mathrm{a}}[\mathrm{mA} / \mathrm{V}]$ | 1.00 |
| $H_{\mathrm{s}_{\text {_dielectric }}} / E_{\mathrm{a}}[\mathrm{mA} / \mathrm{V}]$ | 9.32 |
| $H_{\mathrm{s}_{\text {_metal }}} / E_{\mathrm{a}}[\mathrm{mA} / \mathrm{V}]$ | 9.09 |


|  | MCT-16 |
| :---: | :---: |
| Dielectric constant $\varepsilon_{\mathrm{r}}$ | 16.66 |
| Dielectric loss tangent $\delta$ | $3.43 \mathrm{e}-5$ |
| Periodical length $L[\mathrm{~mm}]$ | 8.3333 |
| Phase advance | $120^{\circ}$ |
| Inner radius $R_{\text {in }}[\mathrm{mm}]$ | 3.0 |
| Outer radius $R_{\text {out }}[\mathrm{mm}]$ | 4.6388 |
| Frequency $[\mathrm{GHz}]$ | 11.9940 |
| Unloaded $Q_{0}$ | 2829 |
| $r^{\prime} / Q_{0}[\Omega / \mathrm{m}]$ | 9368 |
| $r^{\prime}[\mathrm{M} \Omega / \mathrm{m}]$ | 26.5 |
| $v_{\mathrm{g}} / \mathrm{c}$ |  |
| $E_{\mathrm{s}} / E_{\mathrm{a}}$ | 0.066 |
| $H_{\mathrm{s}} / E_{\mathrm{a}}[\mathrm{mA} / \mathrm{V}]$ | 1.07 |
| Power <br> $100 \mathrm{MV} / \mathrm{m}[\mathrm{mW}]$ | 9.32 |
|  | 280 |

## EM fields in matching section



The fields in the matching section are weaker than those of DLA.

## Tolerance studies



## Accelerating field



## Simulated S-parameters



## Mode converters with a choke



## DLA structure



Courtesy of photos from Dr. Chunguang Jing, Euclid Techlabs.

## RF Measurement on assembly of two TE10TM01 mode converters and the DLA structure



## S-parameters comparison




$\square$ From the measurement blue line at the frequency of $11.994 \mathrm{GHz}, S_{11}^{\prime}=$ $-11.35 \mathrm{~dB}, S_{21}^{\prime}=-6.34 \mathrm{~dB}$;
$\square$ There is a big discrepancy between the measured and simulated S parameters.

## Summary \& Outlook

■ An X-band DLA structure with the TE10-TM01 mode converters and matching sections is designed, fabricated, and low-power measured.
■ The fabrication error may cause the big discrepancy between measured and simulated Sparameters.

■ Using two power splitters for 2-port testing on the DLA structure (Large power loss results from HOMs' propagation due to the asymmetries in the 4-port testing).

